

10/544178

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Attorney Docket: 061063-0317066
Client Reference: OSP-18862

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re National Stage Application of
PCT/JP2003/0132171 to OKUBO ET AL.
Application No.:

Confirmation Number:

Group Art Unit:

Filed: August 1, 2005

Examiner:

Title: INSPECTION METHOD, MANUFACTURING METHOD OF PIECE FOR
ANALYSIS, ANALYSIS METHOD, ANALYZER, MANUFACTURING METHOD OF SOI
WAFER, AND SOI WAFER

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Before beginning examination, please amend the above-identified National Stage
application as follows:

Client/Matter: 061063-0317066

IN THE TITLE:

Please delete the Title of the Invention as presented in the International Stage and insert the following title therefor:

INSPECTION METHOD, MANUFACTURING METHOD OF PIECE FOR ANALYSIS,
ANALYSIS METHOD, ANALYZER, MANUFACTURING METHOD OF SOI WAFER,
AND SOI WAFER